# **Control Charts**

## An introduction to Statistical Process Control



#### **Course Content**

- <u>Prerequisites</u>
- <u>Course Objectives</u>
- What is SPC?
- <u>Control Chart Basics</u>
- Out of Control Conditions
- <u>SPC vs. SQC</u>
- Individuals and Moving Range Chart
- <u>Central Limit Theorem</u>
- <u>X-bar and Range Charts</u>
- Advanced Control Charts
- <u>Attribute Charts</u>
- Final Points
- <u>Reference Section</u>



- Learners should be familiar with the following concepts prior to taking this course
  - Variation
  - Mean and Standard Deviation
  - Histograms
  - Normal Distributions
  - Cp and Cpk
- <u>Capability Course</u> is available on BPI website if you need to review these topics



### **Course Objectives**

- Upon completion of this course, participants should be able to:
  - Understand the basics of creating variable and attribute control charts
  - Understand the concepts of advanced control charting
  - Identify an out of control condition
  - Identify which control chart to use with each process
  - Calculate contro! limits for any control chart



- SPC is the application of statistical methods to identify and control the special cause of variation in a process
- SPC is a preventative tool to:
  - Assess the consistency of a process
  - Monitor a process to determine when it has changed
  - Reduce variation in a process



**Run Chart** 

 Graph that displays observed data in a time sequence 50 45 40 Values 35 30 25 20 Time



- Run chart with calculated control limits
  - 3 standard deviations above and below average
- Help distinguish process variation due to assignable or "common" causes from those due to unassignable or "special" causes
- Used to detect whether a process is statistically stable



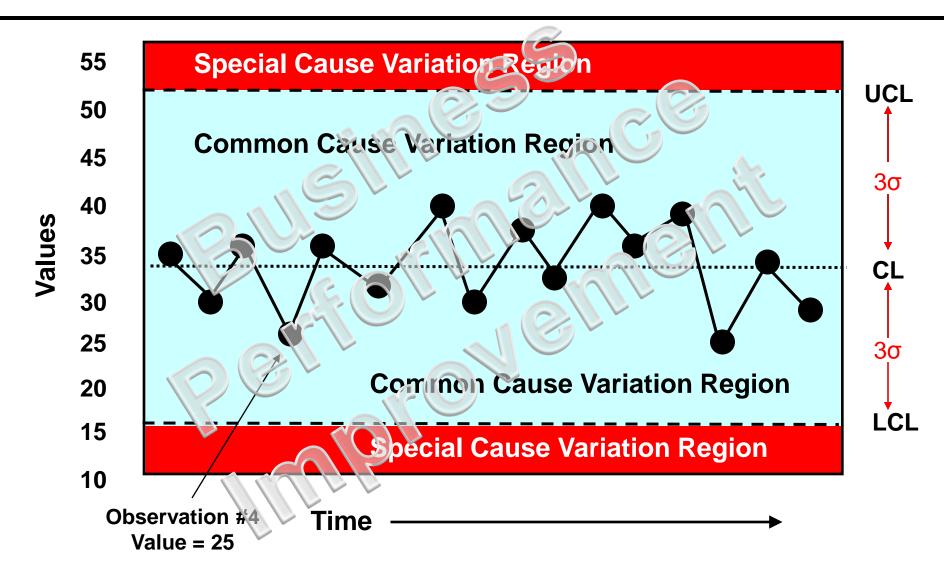
- Invented by Walter A. Shewhart while working for Bell Labs in the 1920s
- W. Edwards Deming became the foremost champion of Shewhart's work
  - long career as an industrial consultant in Japan, spread use of the control charts throughout the 1940s and 1950s



- Special Cause Variation
  - Data points outside of control limits
  - Trend or shift pattern within limits
  - Can be removed from a process
- Common Cause Variation
  - Noise within the system, typical, expected
  - Data points randomly occurring within the control limits
  - Always exists in a process, but can be reduced

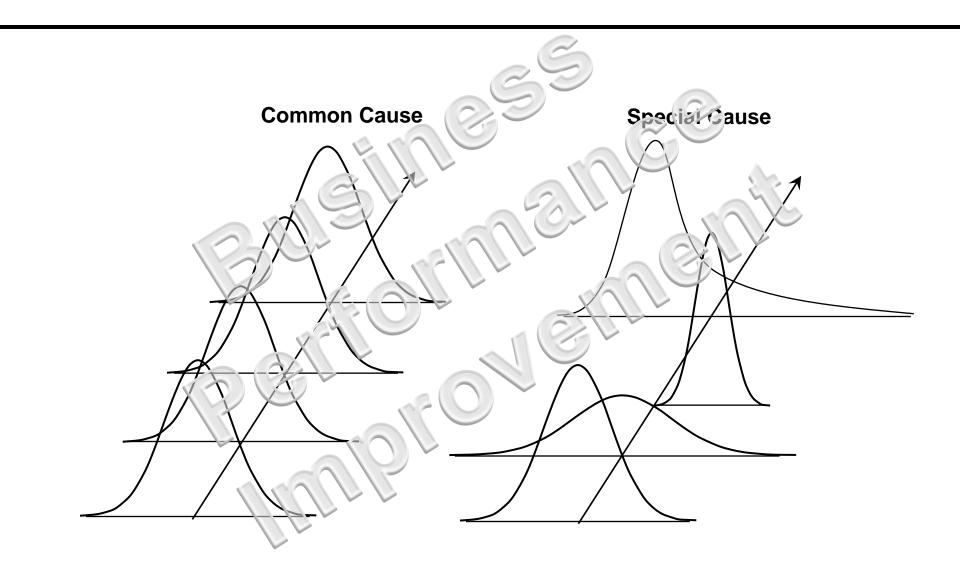


#### **Control Chart Basics**





#### **Special vs. Common Cause**





### **Real Life Examples**

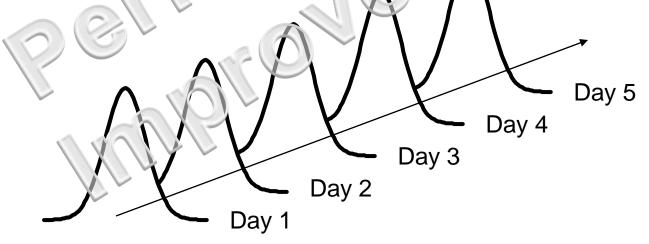
- Process: Driving to Work
- Average Time: 12 minutes
- Standard Deviation: 2.5 minutes
- Common Causes
  - Wind speed, miss one green light, driving speed, number of cars on road, time when leaving house, rainy weather
- Special Causes
  - Stop for school bus crossing, traffic accident, pulled over for speeding, poor weather conditions, car mechanical problems, construction detour, stoplights not working properly, train crossing



- **Centerline** (CL) = average value of observations
- Upper Control Limit (CL) ~ 3 standard deviations ABOVE the centerline
- Lower Control Limit (LCL) 3 standard deviation BELOW the centerline
- Control limits are set when process is "in control" or "stable"
  - Fixed at baseline value
  - Adjusted for improvements
  - Never widened
- Control limits are not specification limits

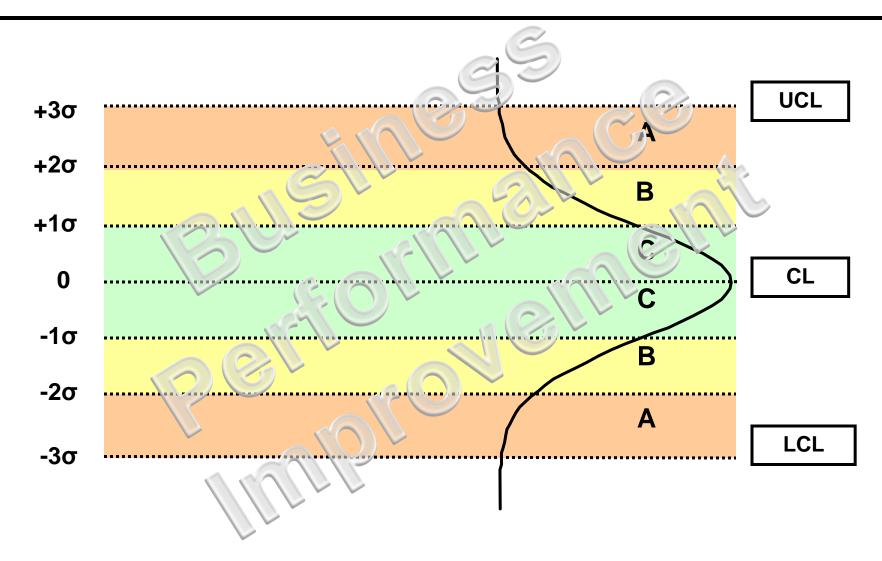


- A process is considered in control" or "stable" when the data does not show any out of control conditions on the control chart
- Stability means predictability

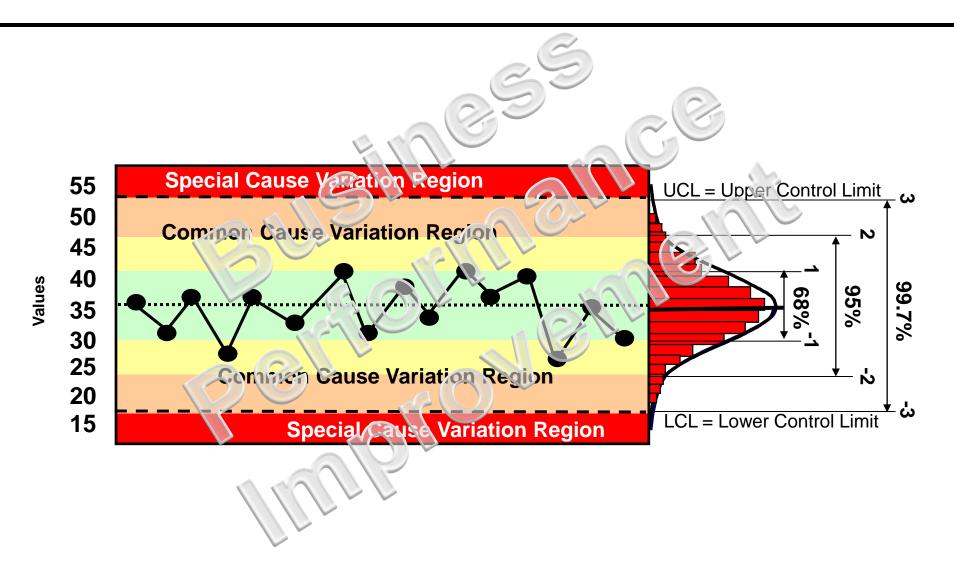




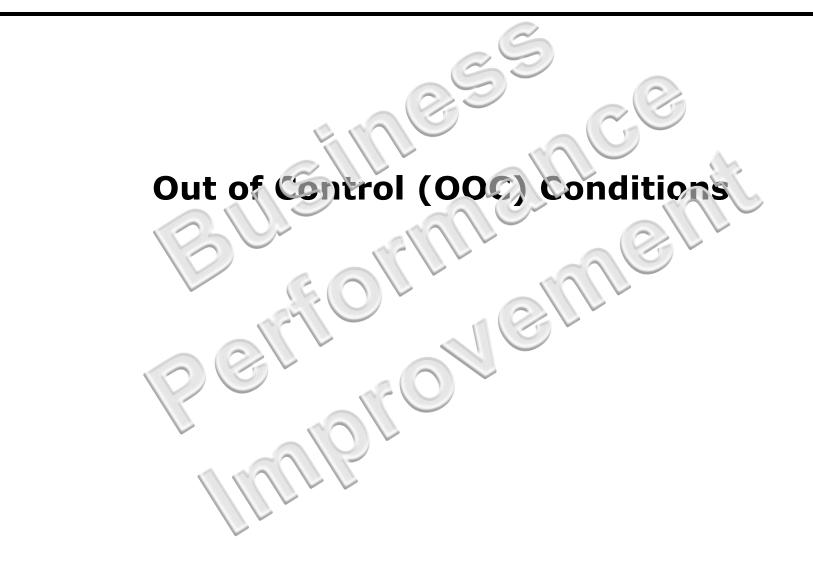
#### **Control Limit Zones**









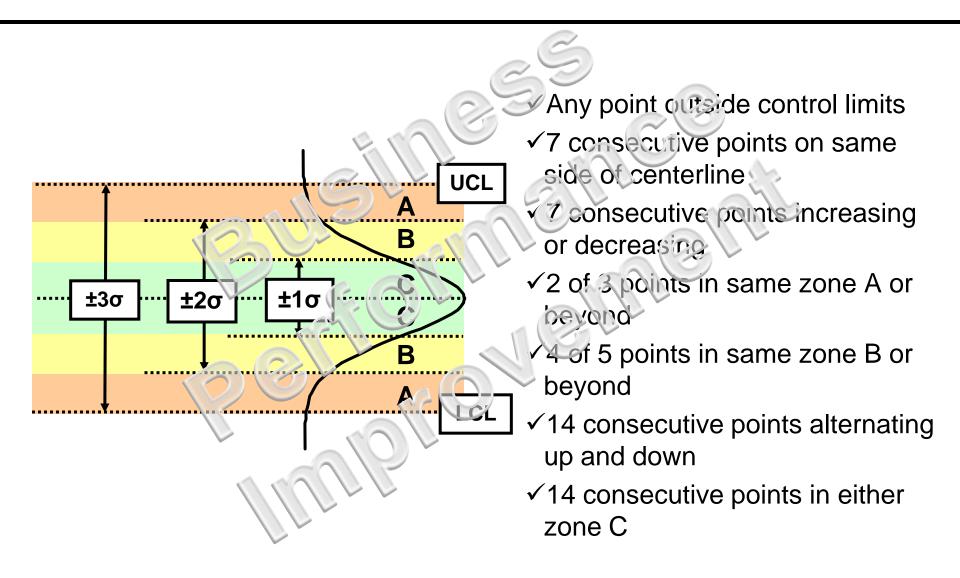




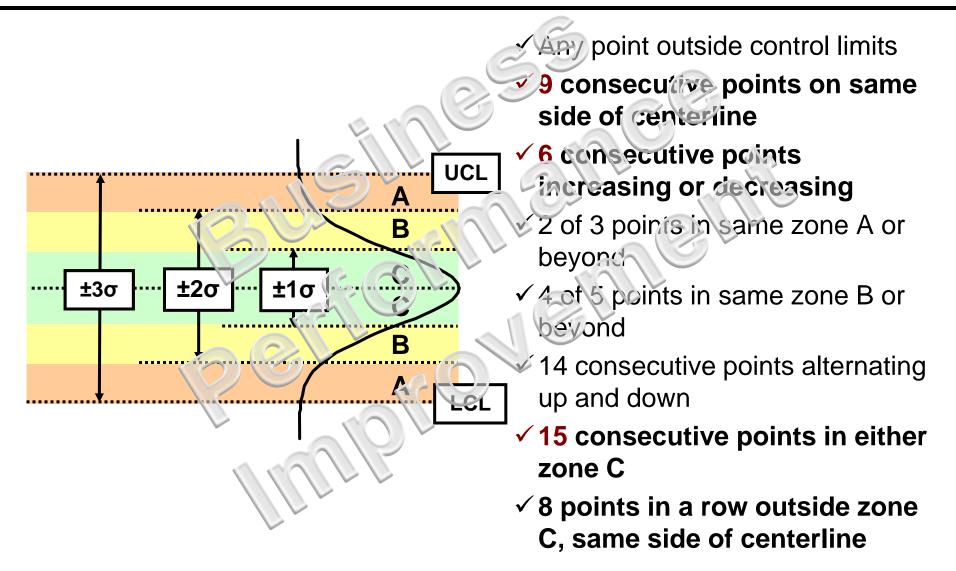
- Outside control limits is easiest to identify
- Patterns highlight other out of control conditions
  - Trends (increasing/decreasing points)
  - Shifts (data jumps higher or lower than normal)
  - Inconsistencies (not random, more or less variation than history)



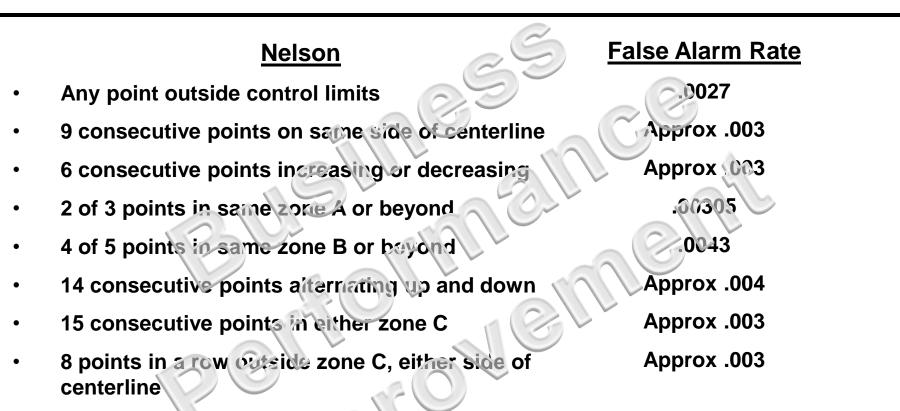
#### **Western Electric Rules for Control**











The Nelson tests are designed so that the false alarm rates for all tests are approximately the same. The Western Electric rules do not have this property.

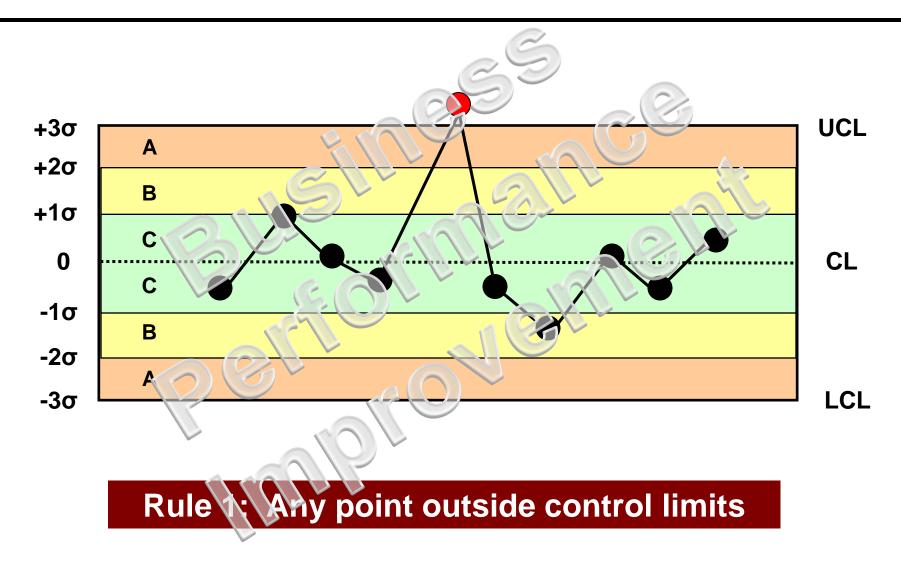


- If process is stable and normal, 50% of data will be above centerline, 50% will be below centerline
- Probability of getting 9 straight on one side, same as flipping coin and getting 9 straight heads

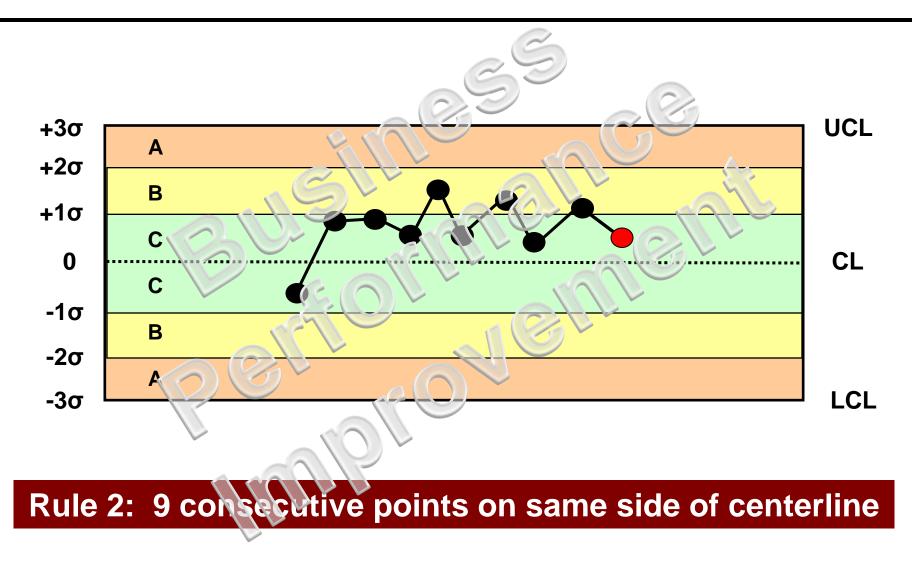
 $(.5)^{10} = 0.5 * 0.5 * 0.5 * 0.5 * 0.5 * 0.5 * 0.5 * 0.5 * 0.5 * 0.5 = .001$  $(.5)^9 = 0.5 * 0.5 * 0.5 * 0.5 * 0.5 * 0.5 * 0.5 * 0.5 = .002$ 

 $(.5)^8 = 0.5 * 0.5 * 0.5 * 0.5 * 0.5 * 0.5 * 0.5 * 0.5 = .004$ 

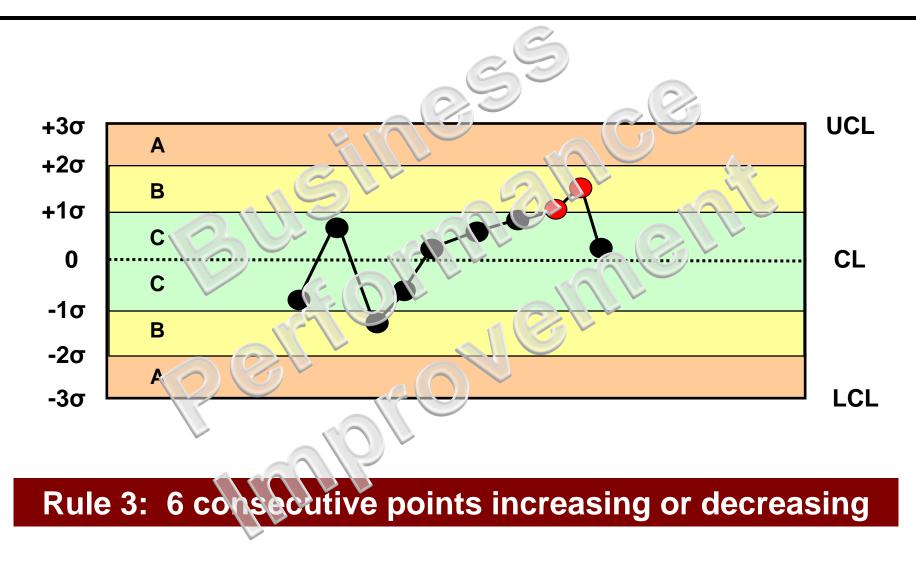




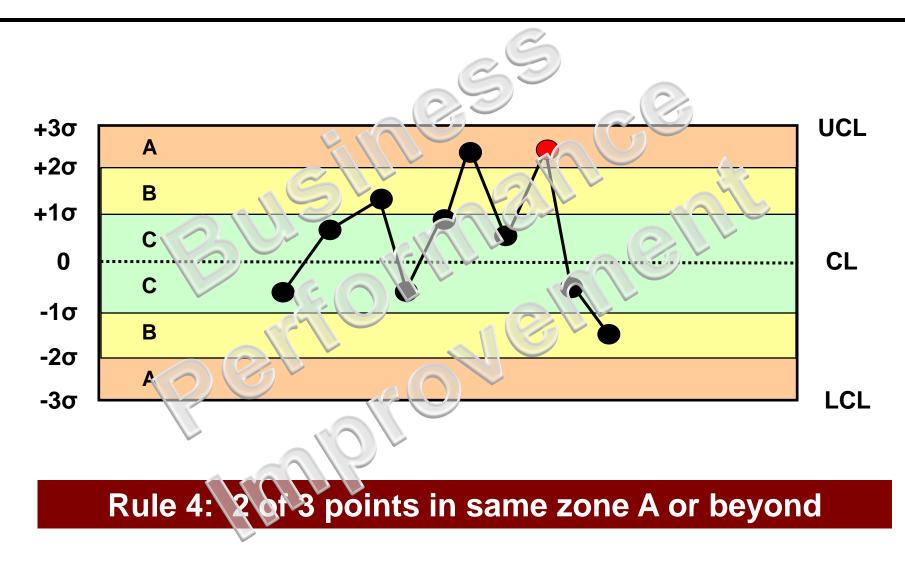




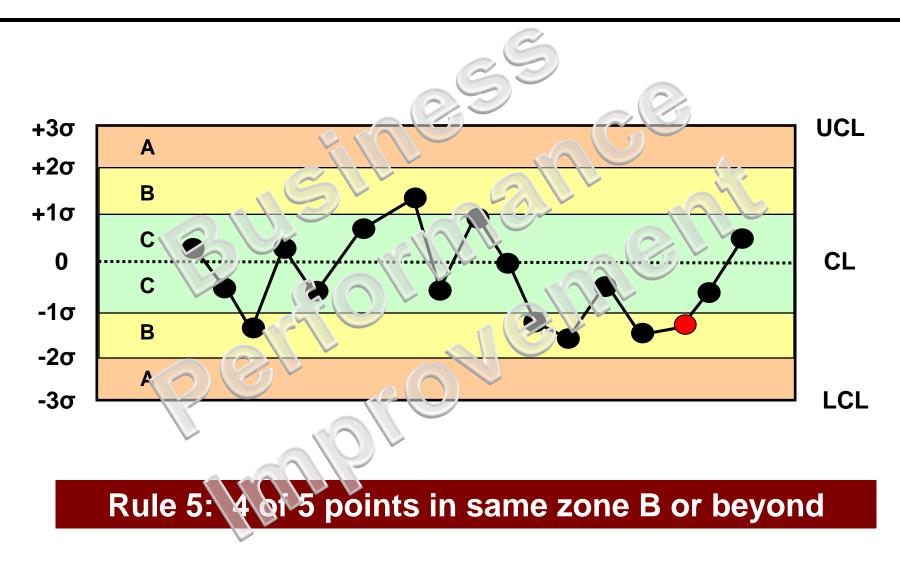




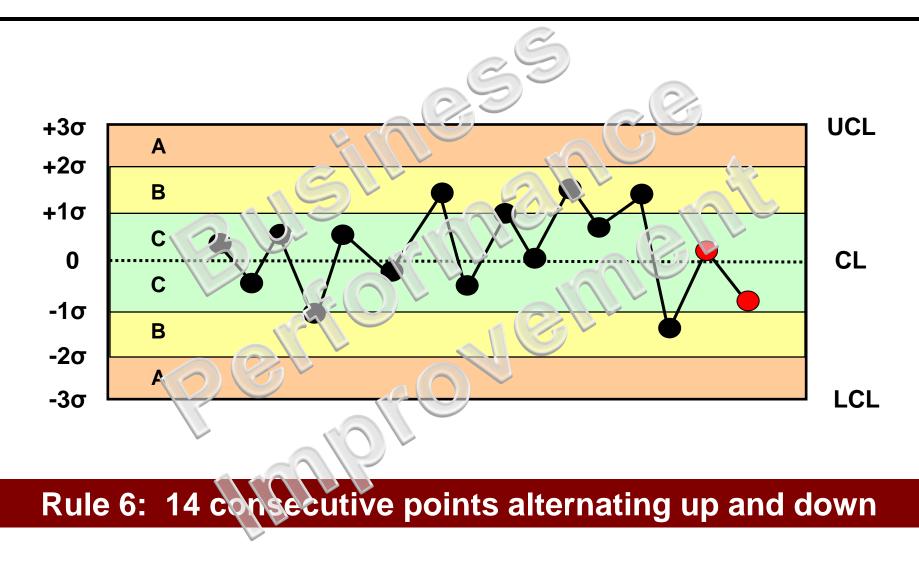




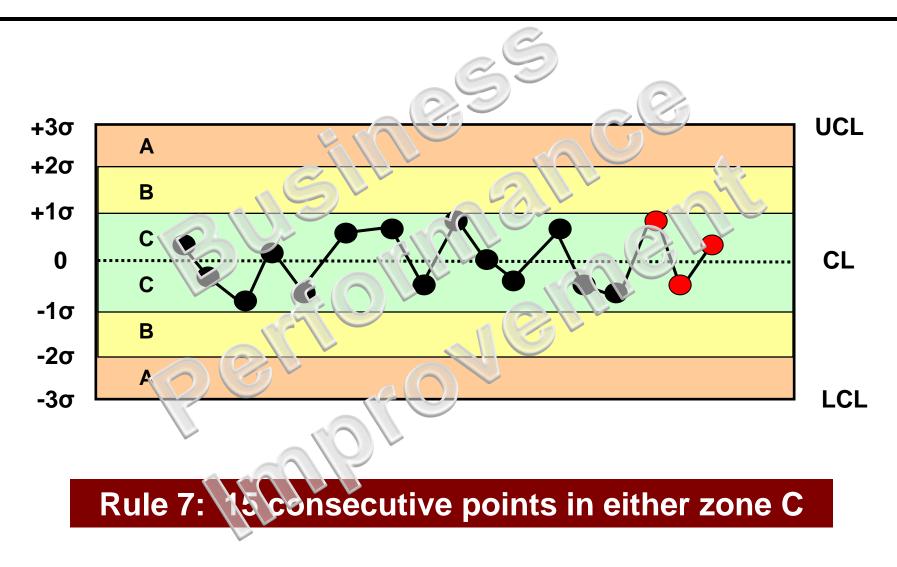




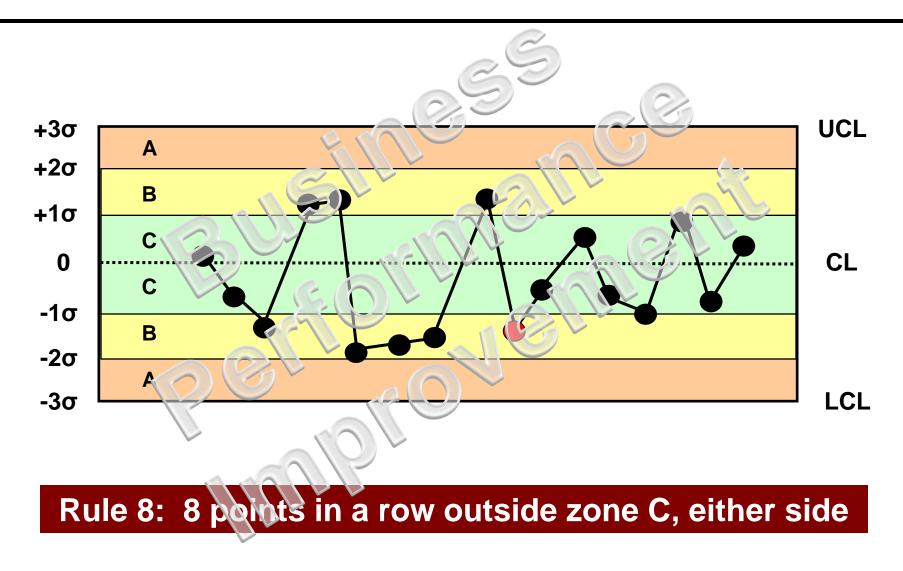






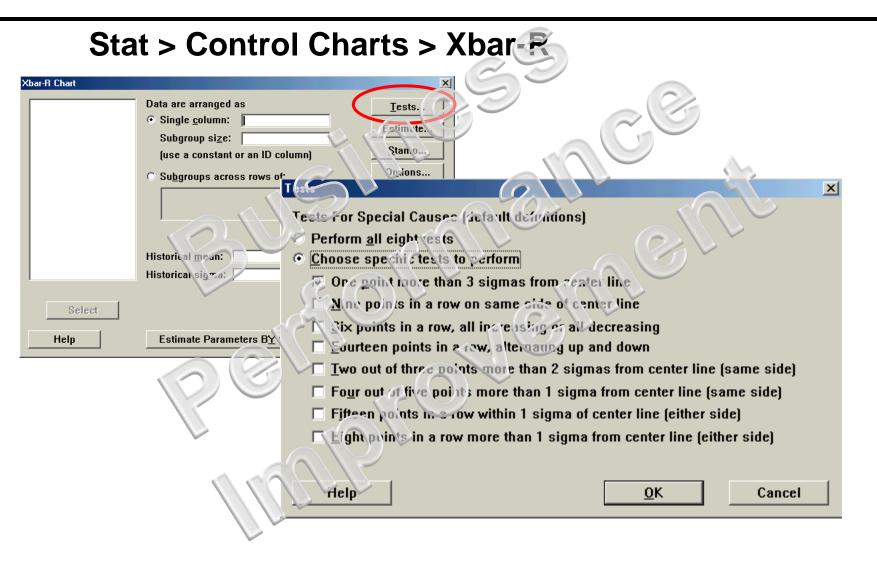






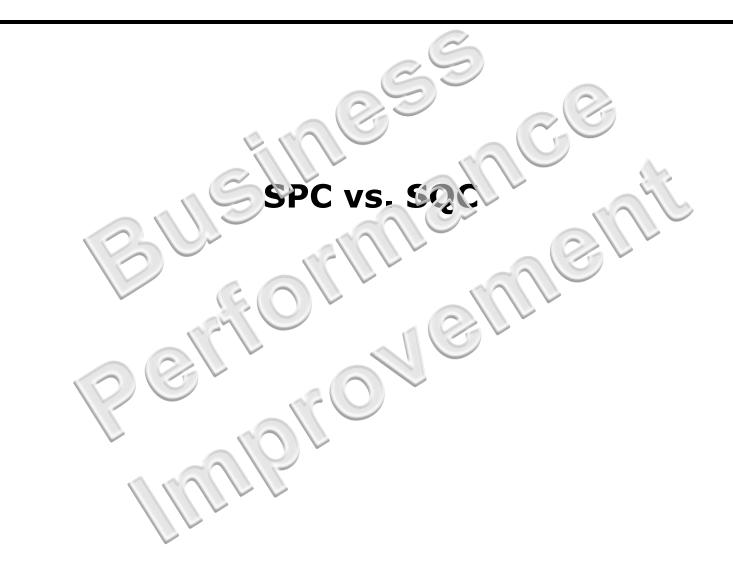


#### **Nelson Tests in Minitab**<sup>™</sup>



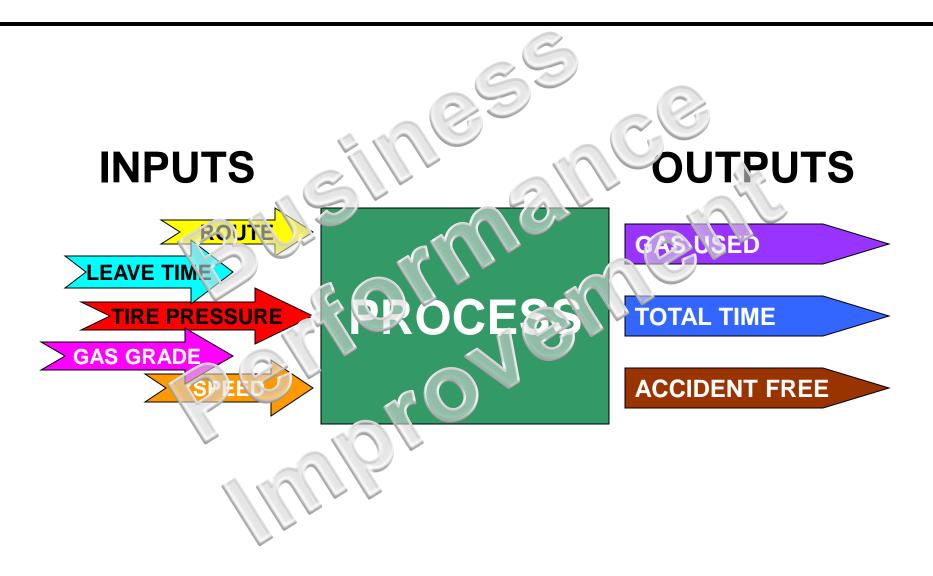
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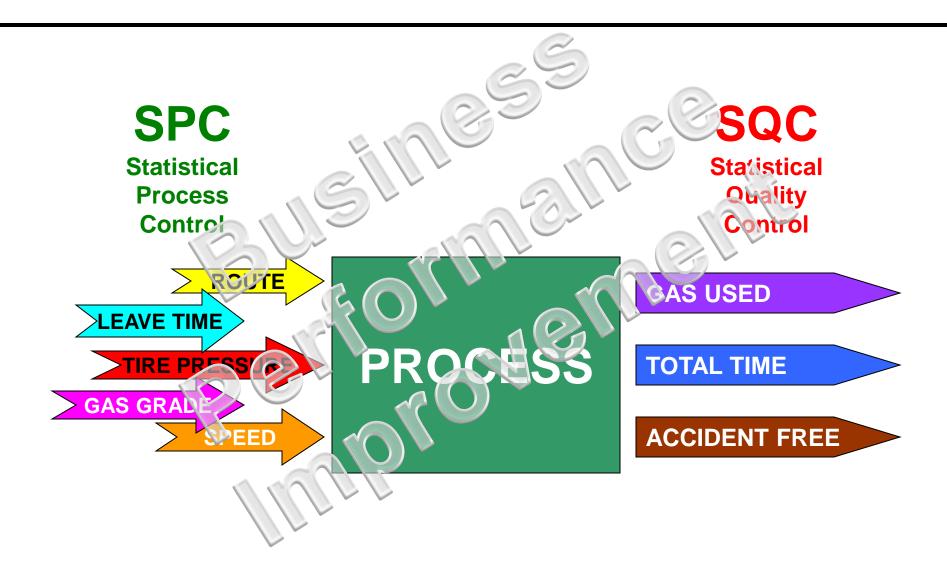


#### **Inputs and Outputs**

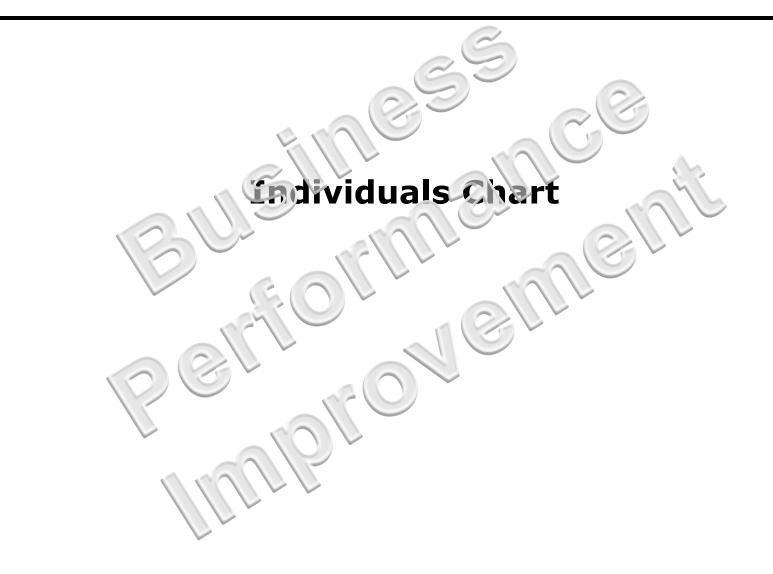




#### **Evolution of control charts**





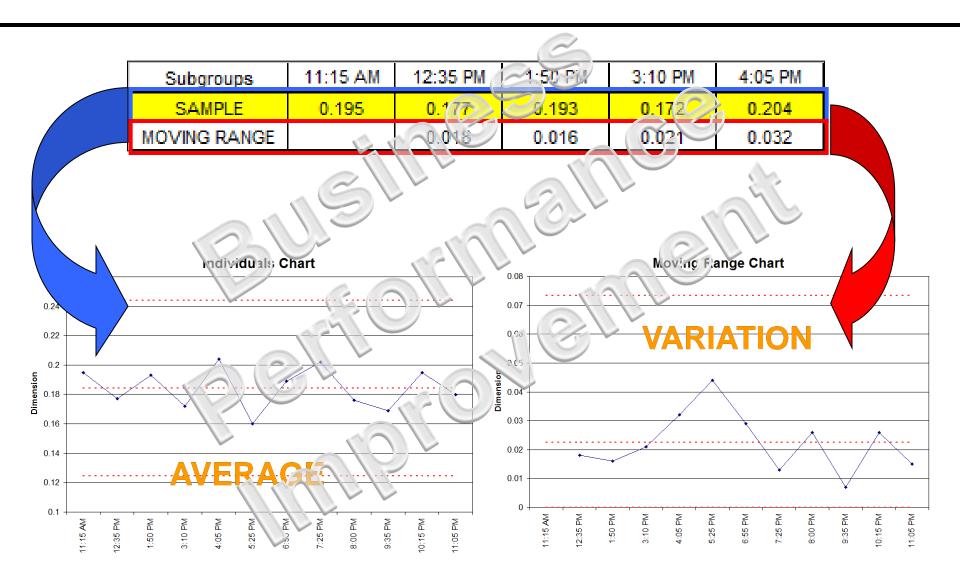




- Most common type of control chart
  - Each individual value plotted over time
  - Difference from previous value to current value plotted on Moving Range chart
  - Moving Range average used to calculate control limits for individual readings



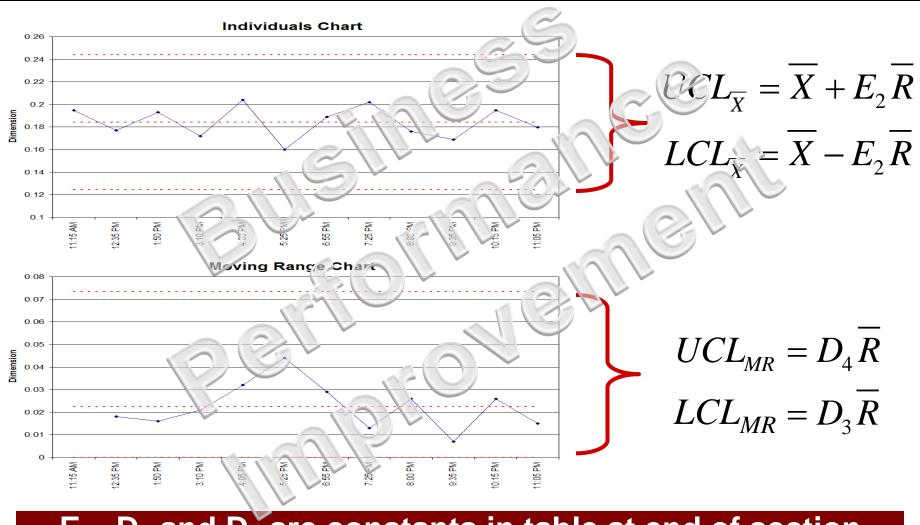
### **Individuals and MR example**



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# **Individuals and MR UCL and LCL**



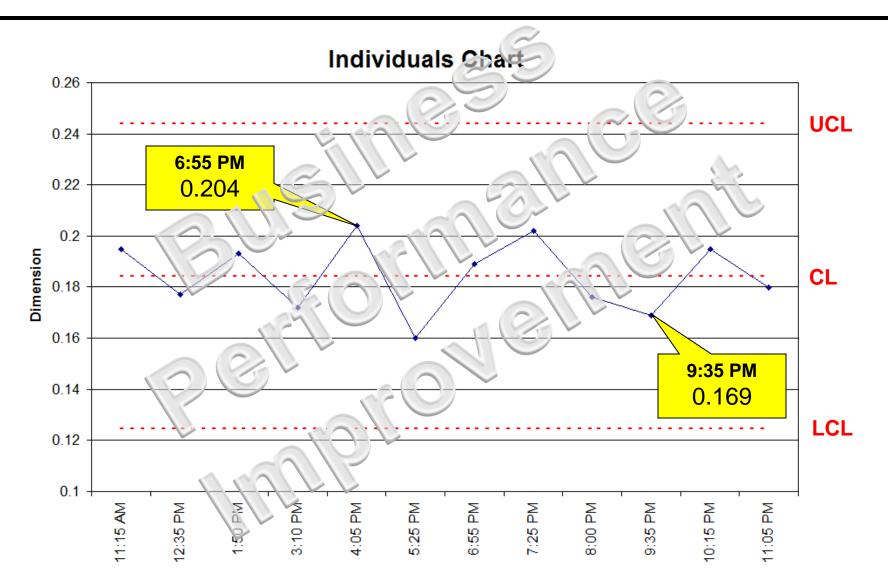


 $E_2$ ,  $D_3$  and  $D_4$  are constants in table at end of section

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#### **Individuals Chart**

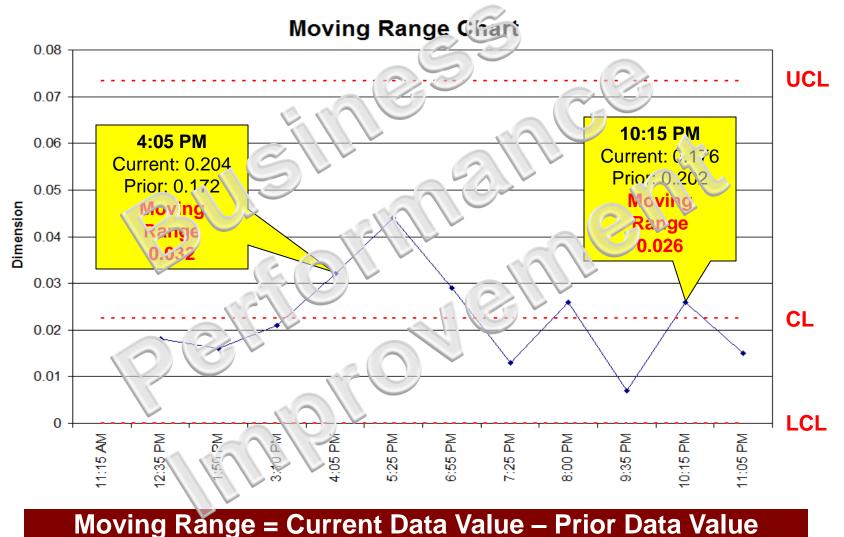




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#### **Moving Range Chart**





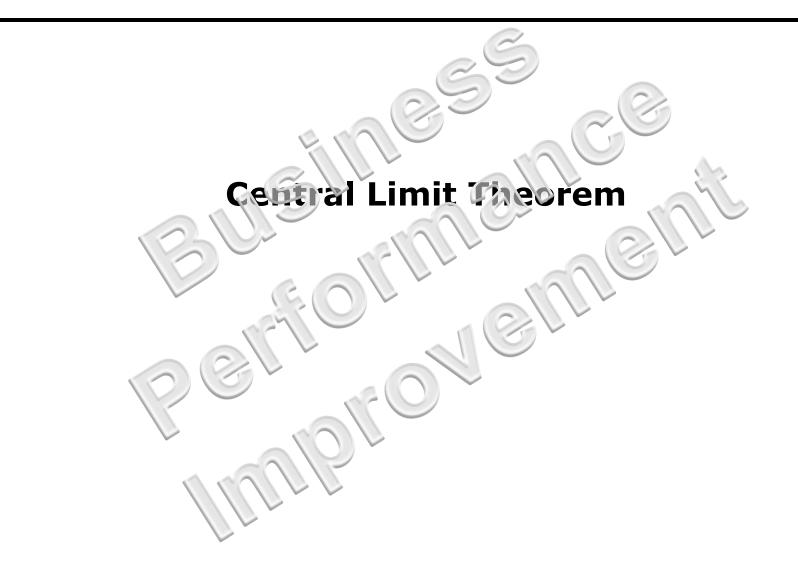
Moving Range – Current Data value – Phor D

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- Individuals control charts cely on assumption that data is normally distributed
- If data does not pass normality test, what can be done?
  - Transform the data (difficult)
  - Use central limit theorem to normalize the data
    - X-bar and R chart does this for you





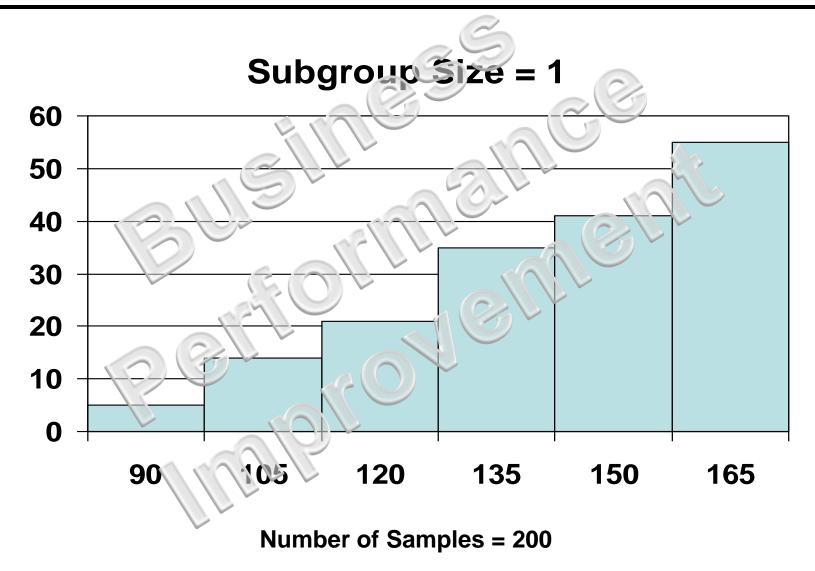


## **Central Limit Theorem**

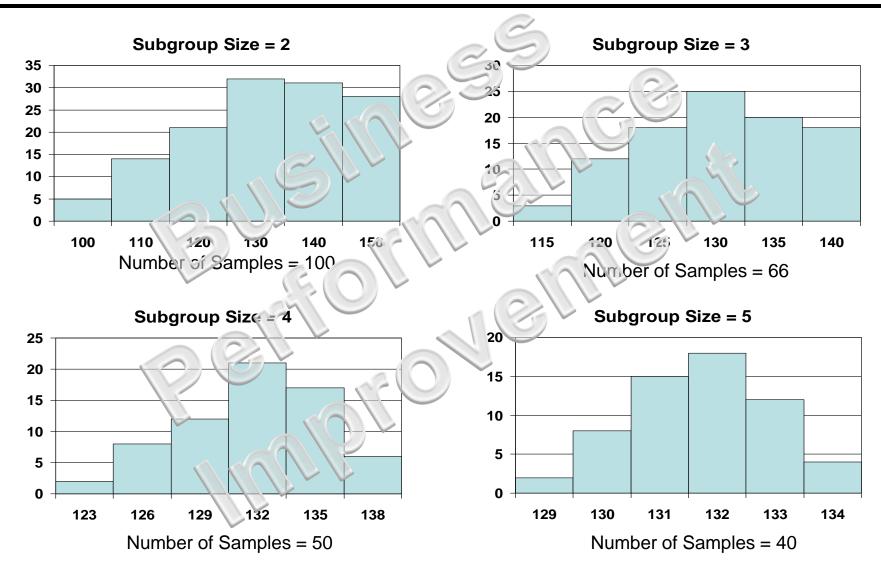
- No matter what the shape of the original distribution (non-normal), the sampling distribution of the mean approaches a normal distribution
  - normal distribution is approached very quickly as subgroup size increases



#### **Central Limit Theorem**







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- In order to use Central Limit Theorem, must define the rational subgroups for data set
- Should be grouped in a way to:
  - maximize the chance of detecting shifts in process average (between subgroups)
  - minimize the variation (range) between samples within the subgroup (within subgroups)
- Don't subgroup different machine setups, different time of day, material differences, operators, or any other variables



- If you analyze the average of a subgroup, not the actual data values, it will be normallydistributed
- X-bar and R Chart applies Central Limit
  Theorem
  - Any data set can use the X-bar and R chart, regardless of data distribution (even nonnormal)





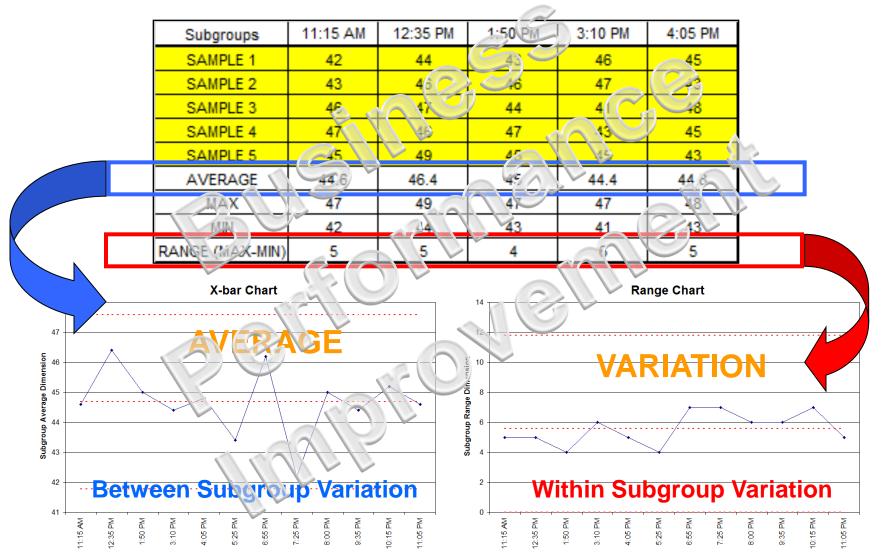
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- Can be used with any distribution of data
- Separates variation into two groups, for ease of investigation
  - Between subgroup (X-bar chart)
  - Within subgroup (Range chart)
- Quicker identification of out of control conditions than Individuals chart



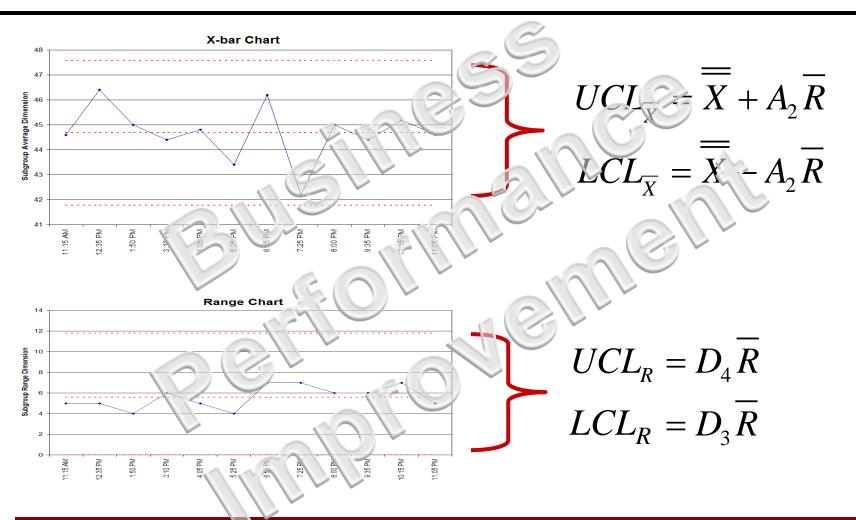
### **X-bar and R example**



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#### X-bar & R UCL and LCL

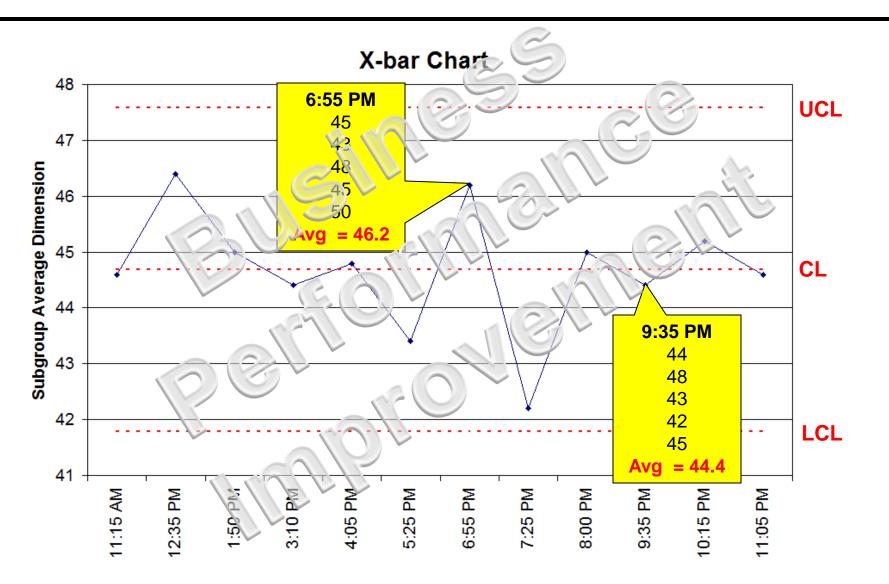


 $A_2$ ,  $D_3$  and  $D_4$  are constants in table at end of section

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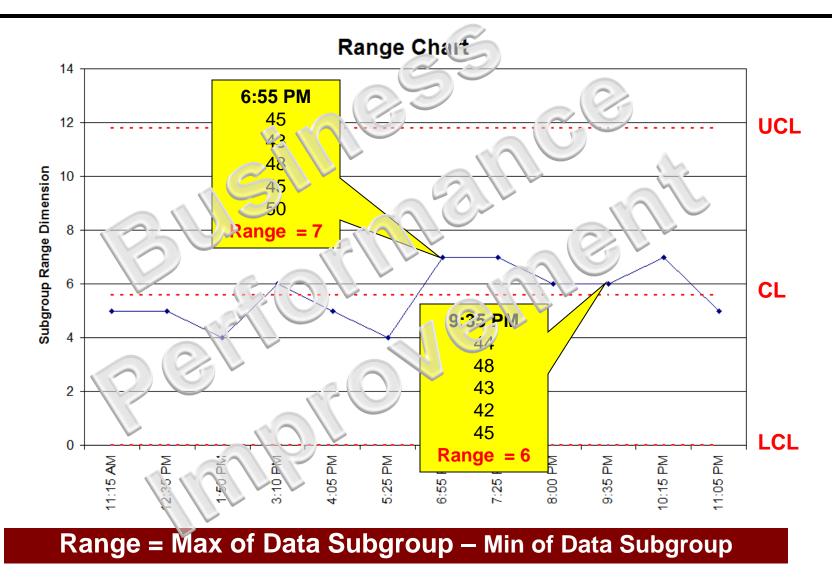


#### Average (X-bar) Chart





#### **Range Chart**



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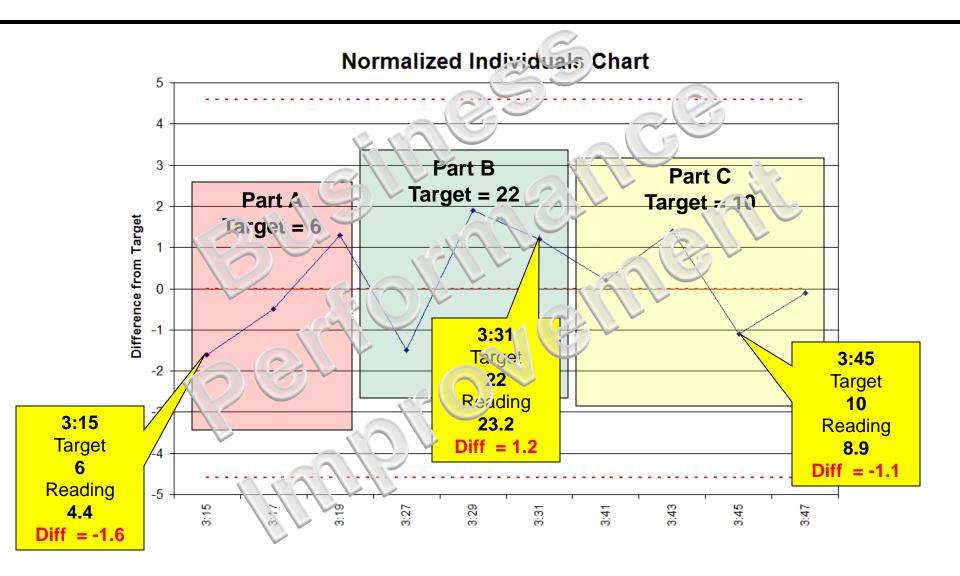


- If operating in a low volume situation, it is usually more practical to use one control chart for several parts or transactions
  - Data must be "normalized" before it is plotted to account for different spec limits of the data
- Process may have different limits or targets, want to know now close process is to target
  - Forecasting (Actual v Predicted), product differences from same process, etc
  - Instead of plotting actual value, plot difference from nominal, target or expected



- Data should be from the same process
- Data should have similar variation
- Requires more data points to setup than traditional charts
- Uses same calculations as traditional charts, except use normalized values







- As processes improve reduce sampling frequency and/or subgroup size
  - Reduce as Cpk increases
  - More efficient use of resources
  - If process goes out of control, increase sampling frequency until process stabilized
- Concerns with reduced sampling
  - Less sensitive to small shifts in process
  - Can be harder to setup process for random sampling, than capturing all measurements



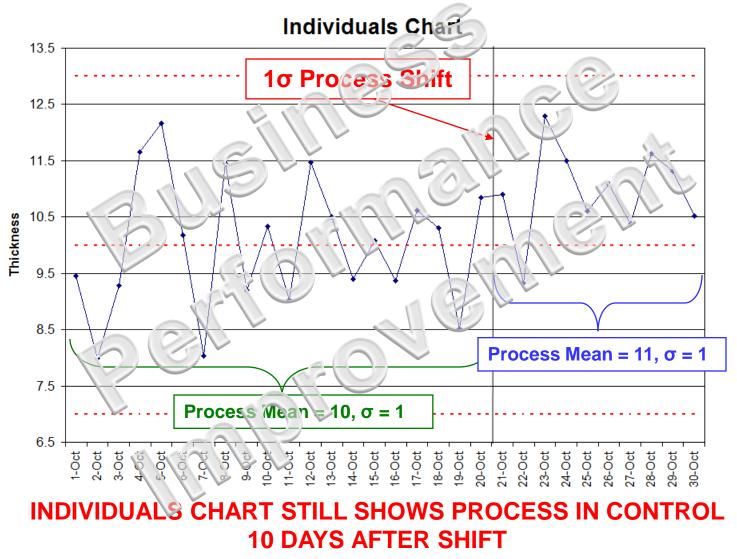
- Determine which process characteristic needs to be controlled
- Determine where in the process the control chart should be implemented
- Determine type of data needed to control process
- Choose the correct type of control chart
- Collect and calculate subgroup data
- Calculate centerlines and control imits
- Plot the data on the chart
- Interpret the chart for out of control conditions
- Improve process based upon analysis of control chart







### **Small Shift Example**



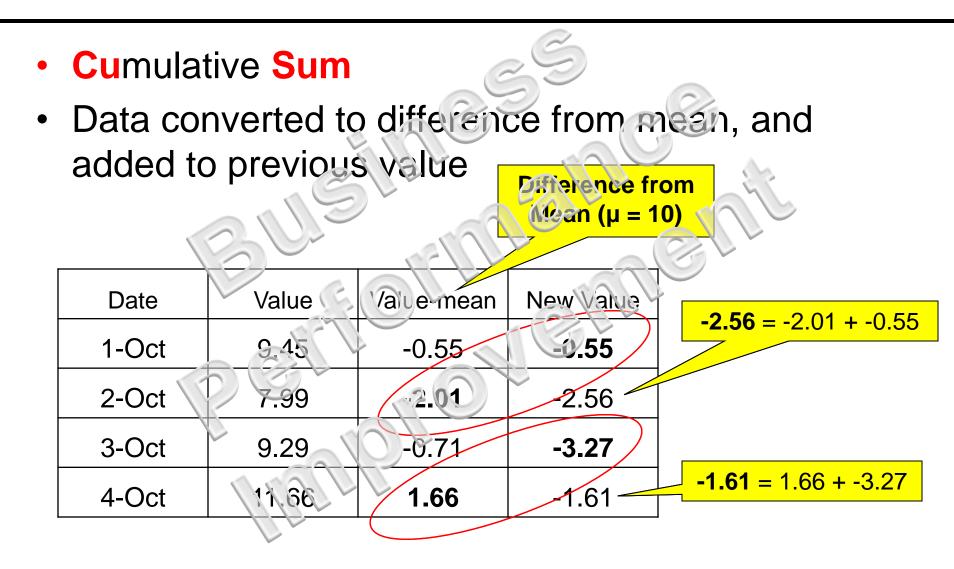
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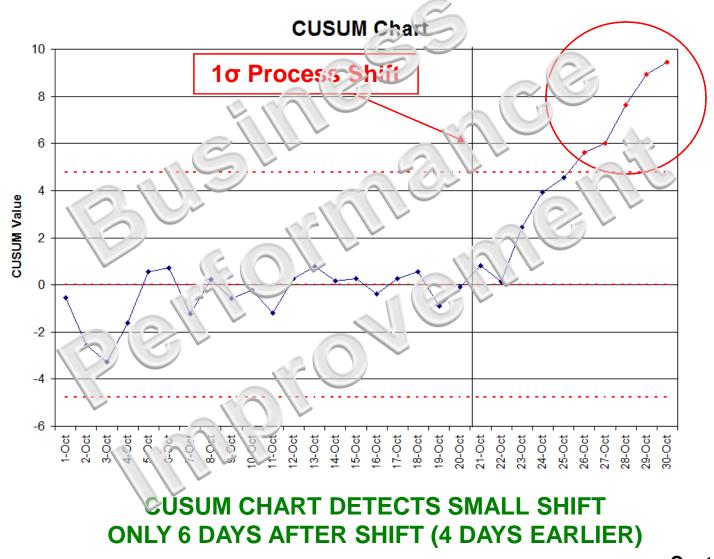
- Typical control charts don't use prior readings, only current data point
  - Make small shifts hard to detect (typically less than 1.50)
- Use prior readings in calculation of current data point to detect small shifts
- Two alternative charts are CUSUM and EWMA

CUSUM









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Table for obtaining CUSUM limits sumilar to Shewhart control charts

k	0.25	0.5	0.75	10	1.25	1.5
Mean Shift	0.5	1.0	155	2.0	2.5	3.0
Decision (b)	8.01	4.7	3.34	2.52	1.99	1.61

Example: To detect a mean shift of 1.5 standard deviations, you would set k = 0.75, and the limits on the CUSUM chart would be computed using  $h^*\sigma$  (3.34 $\sigma$ ), which would be 3.34(1) = ± 3.34

Prior example used shift of  $1\sigma$ , k=0.5 and h=4.77, so limits were set at ±4.77



- Exponentially Weighted Moving Average
- Good for detecting small shifts in processes
- Better at detecting large shifts than CUSUM
- Uses prior readings in calculation of current data point

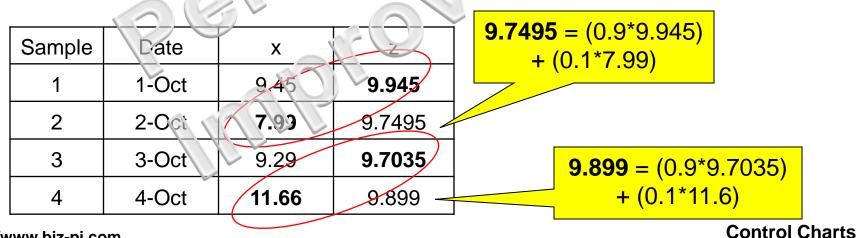
- the further away, the less influence

 Best if used with data from individuals chart (subgroup size = 1)



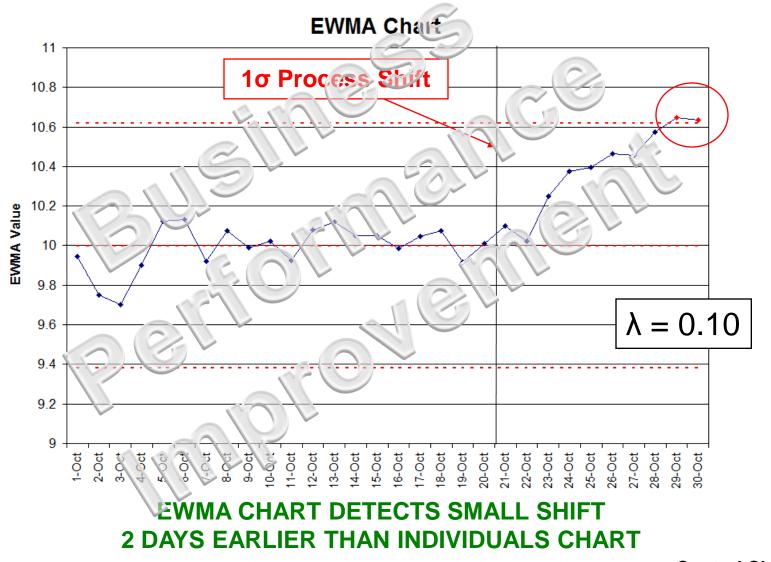
- Determine  $\lambda$  (between 0 and 1)
  - $\lambda$  is the proportion of current value used for calculating newest value
  - Recommend  $\lambda = 0.10, 0.20 \text{ or } 0.40$  (use smaller  $\lambda$  values to detect smaller shifts)
- Calculate new z values using  $\lambda = 0.10$

 $Z_i = \lambda^2 X_i + (1 - \lambda)^* Z_{i-1}$  (where i = sample number)



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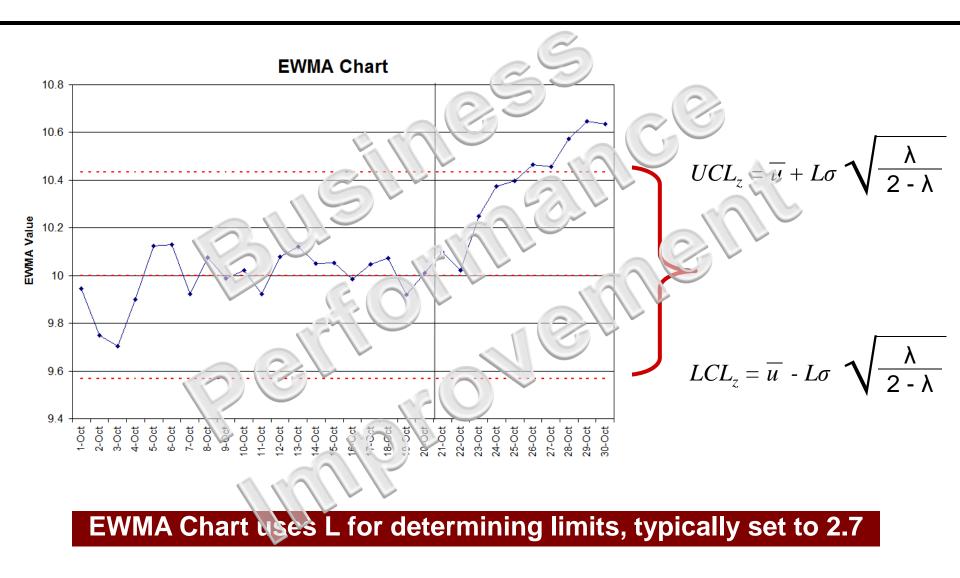




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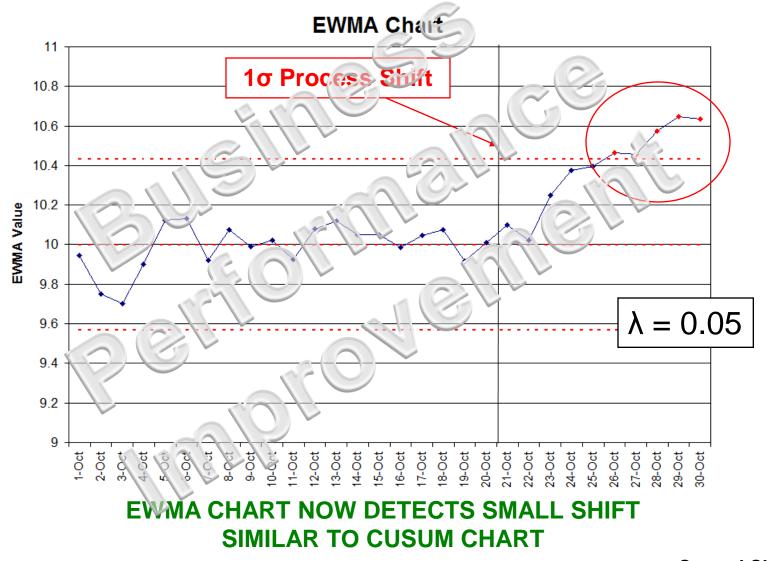
### **EWMA UCL and LCL**







### **EWMA Chart detects shift even earlier!**



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# • CUSUM

 Uses current reading difference from mean, and previous CUSUM value, equally weighted

- EWMA
  - Uses weighted current reading and weighted previous EWMA value
  - Weight of each value is determined by user, based on needs of chart



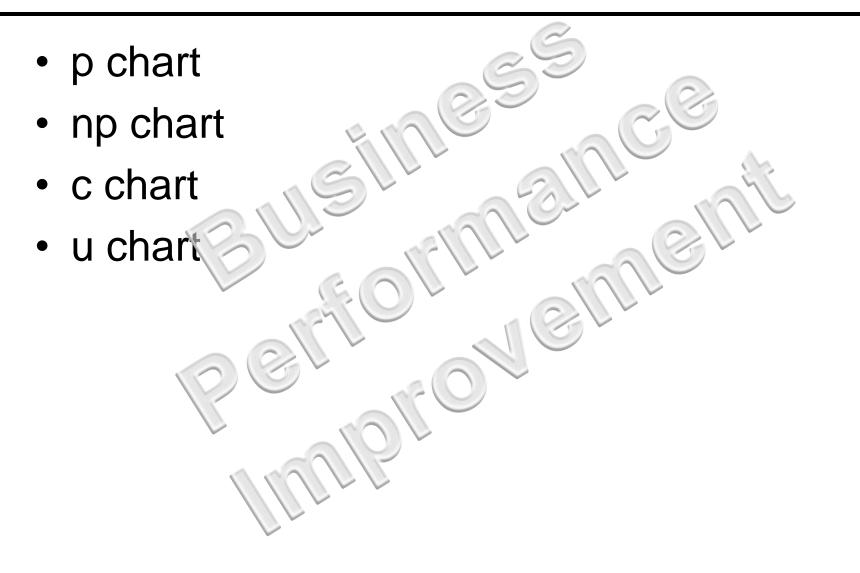
- Cannot quickly detect large shifts in process, like traditional control charts
- Use CUSUM and EWMA for detecting small shifts, Individuals and X-bar charts for larger shifts
  - Ideally, use both within the process, to detect both small and large shifts, with limits set to ±3.50







# **Attribute Control Charts**





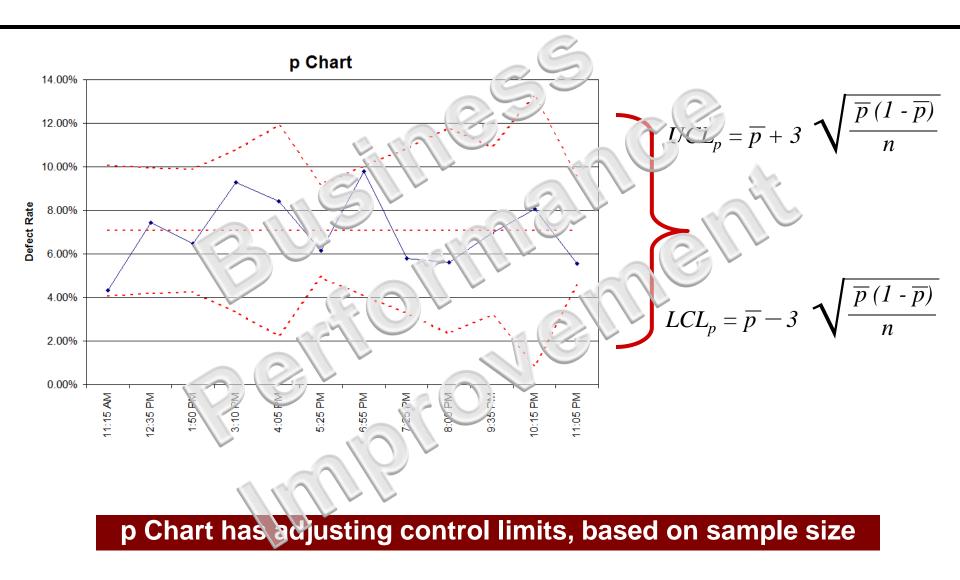
p chart

- Plots the percentage of detectives within a sample
  - 3 red defective parts out of 20 parts p = 3/20 = 15% detect rate

Use when sample size varies
 – Control limits adjust according to sample size

# p chart UCL and LCL

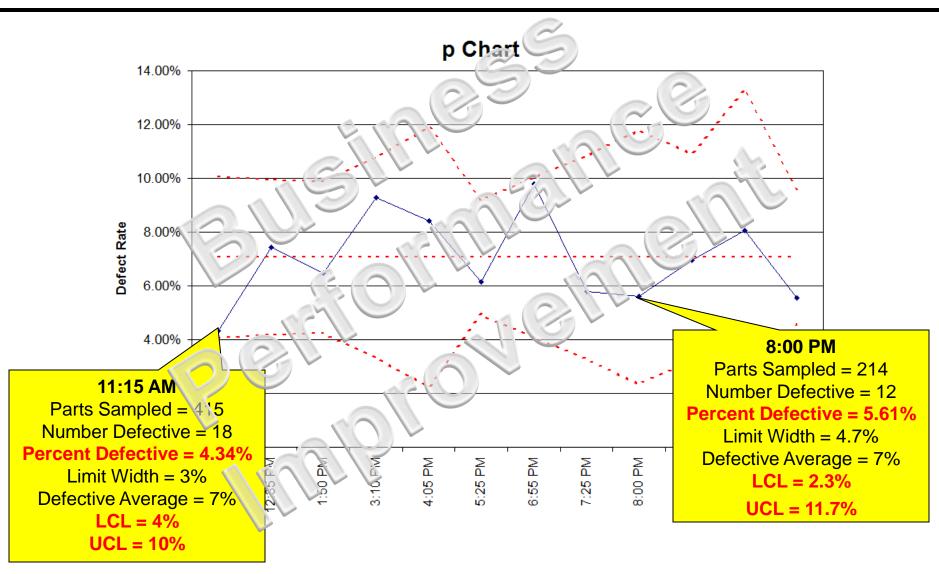




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p chart



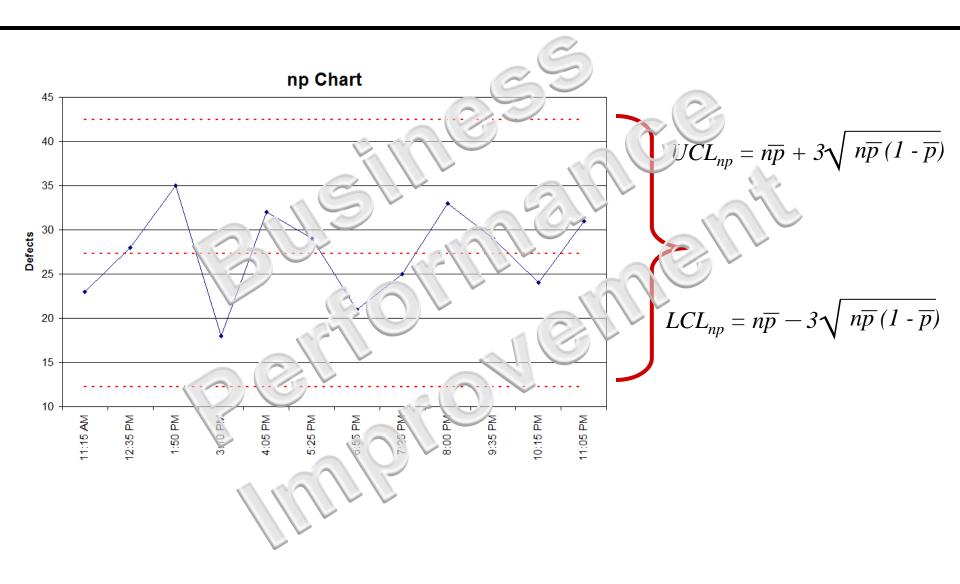
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- Plots the number of defective parts in a sample
- Requires the same sample size each time
- Easy to use, since no calculations required

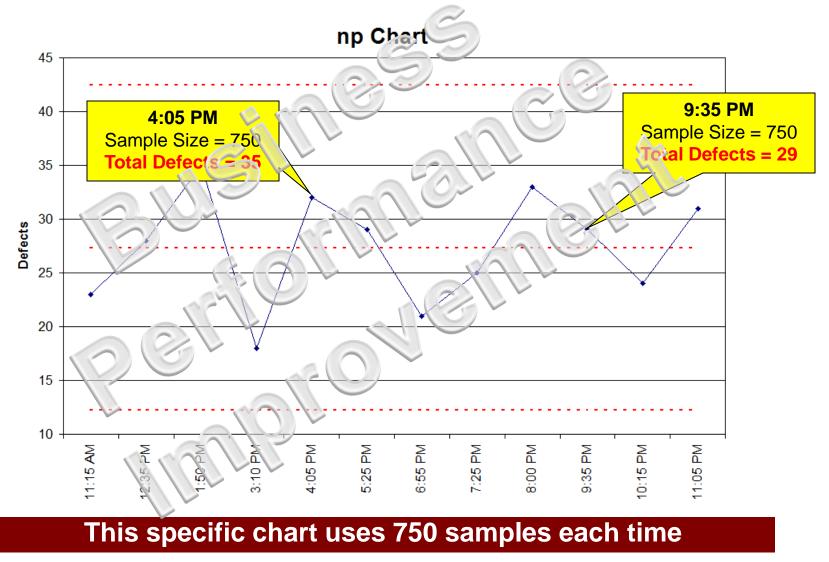
# np chart UCL and LCL







### np Chart



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- Plots the quantity of defects per part in a sample
- Each part can have more than one defect
- Use when sample size varies









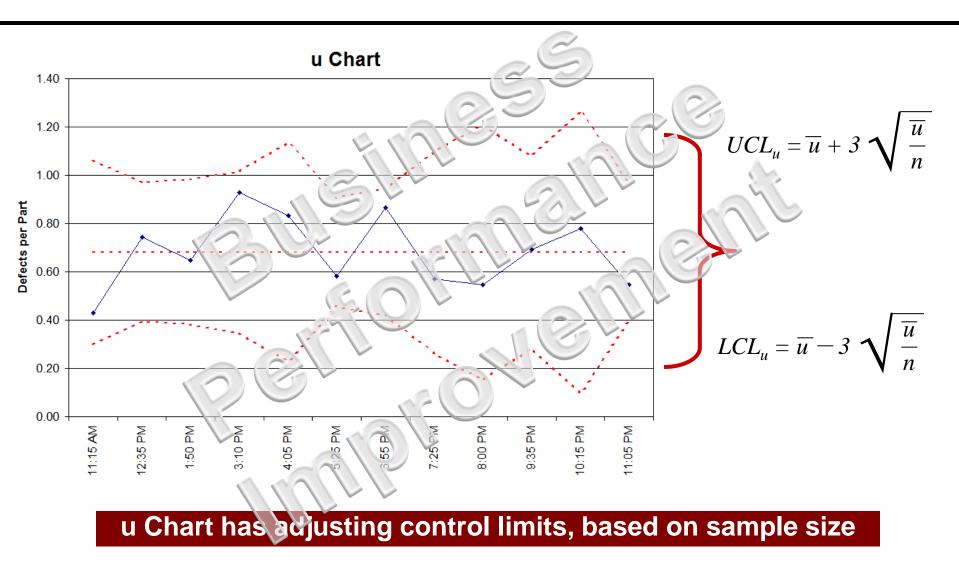


11 total defects found on 6 documents u = 11/6 = 1.833 defects per document whereas p = 4/6 = 67% defect rate

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# u chart UCL and LCL

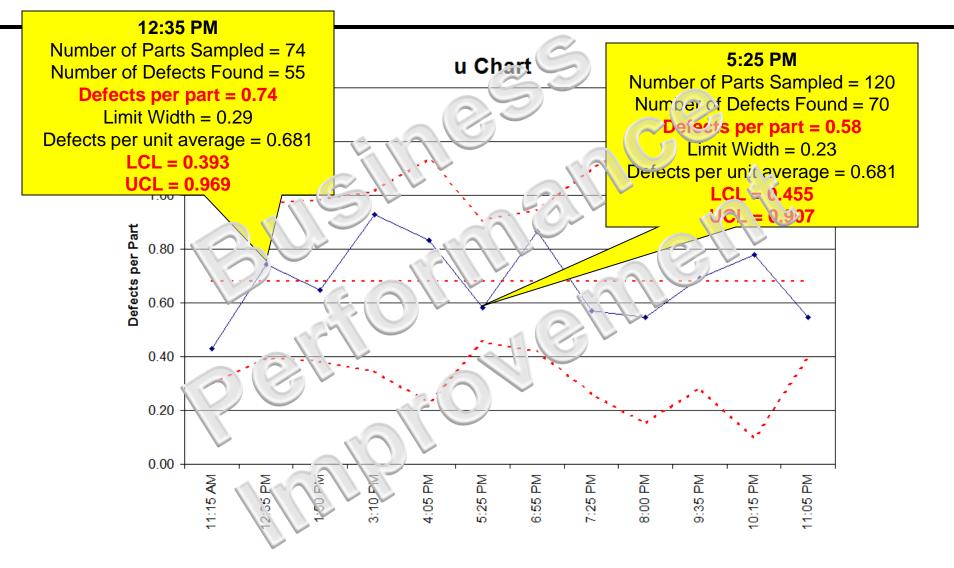




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### u Chart



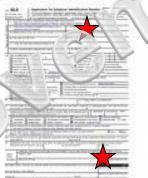


- Plots the quantity of defects in a sample
- Each part can have more than one defect
- Requires same number of parts within each sample

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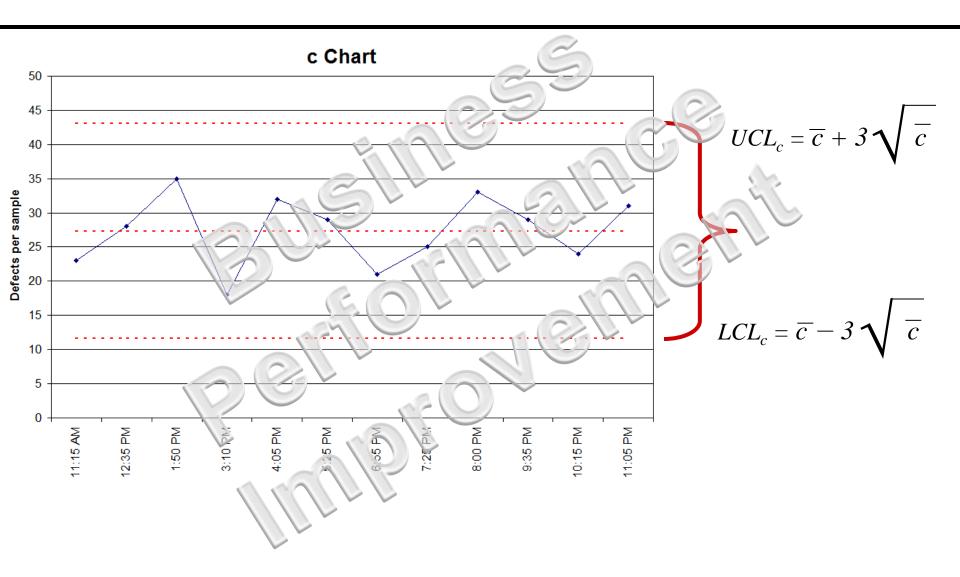




11 total defects found on 6 documents c = 11 defects per sample

# c chart UCL and LCL

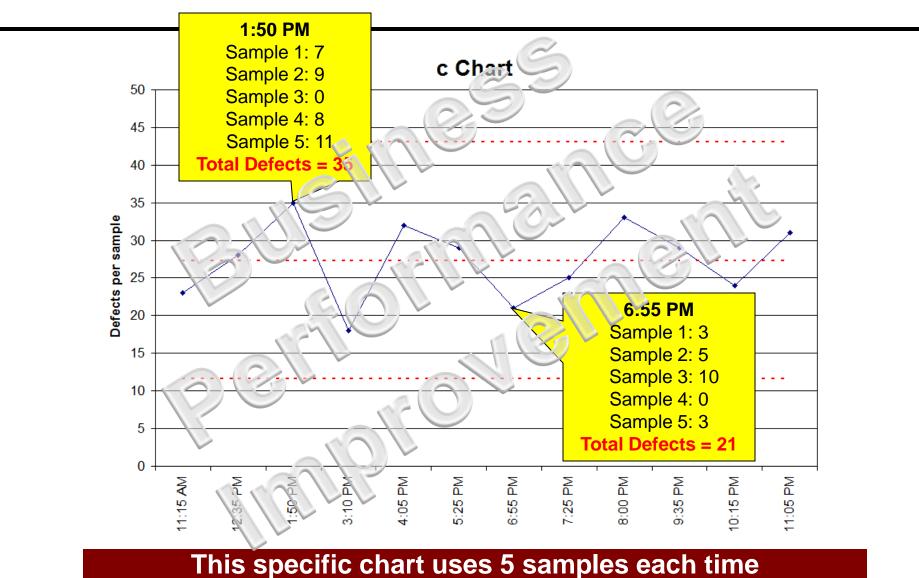




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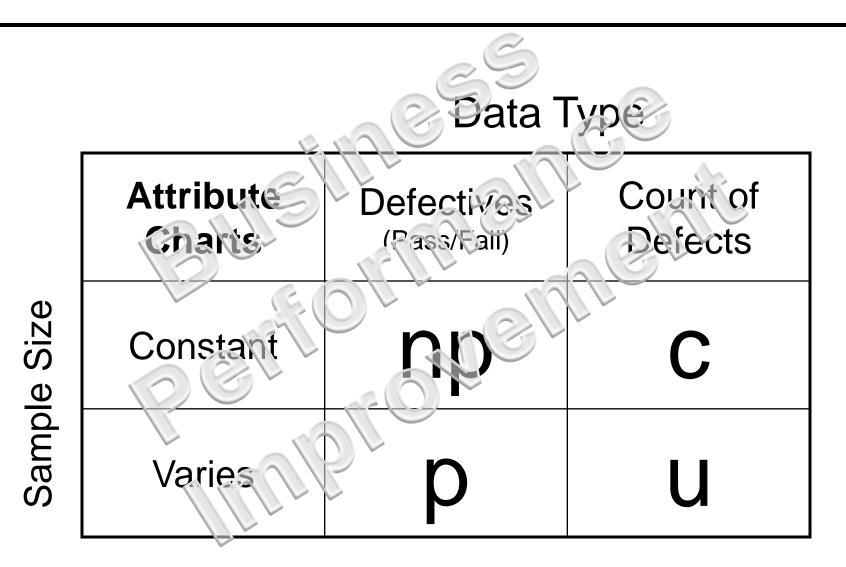
### c Chart



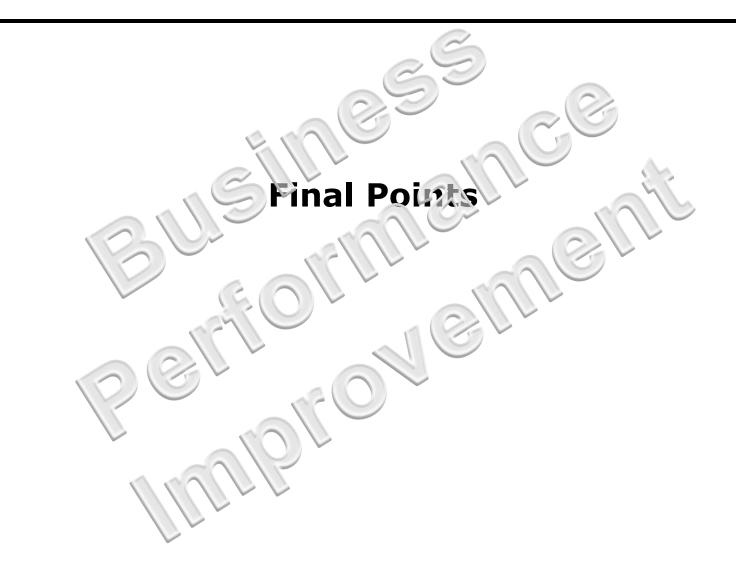
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# **Attribute Selection Chart**



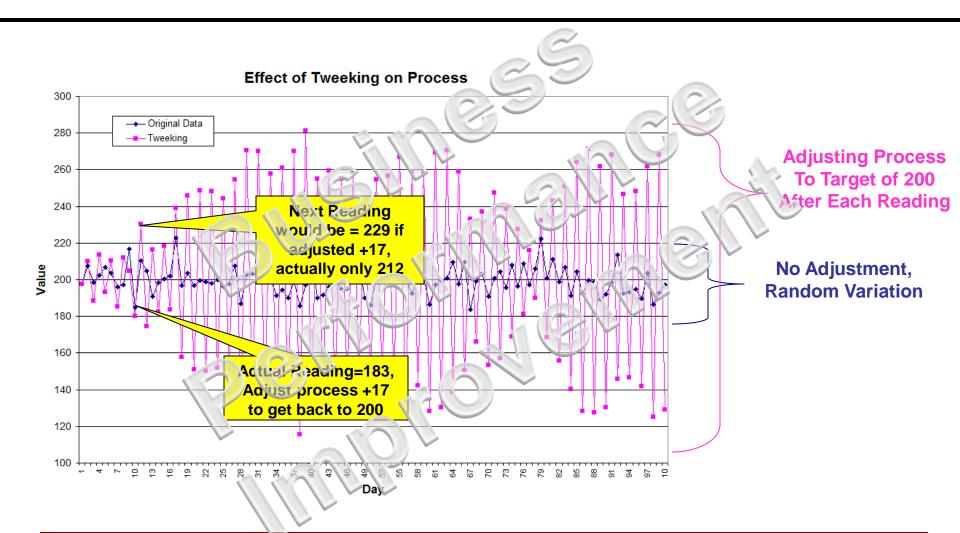






- Phase 1: Control Charts on few process outputs (key quality characteristics)
- Phase 2: Expansion of charts, including numerous attribute control charts
- Phase 3: Some control charts on few process inputs (key process parameters), some converted to Kebar and R charts
- Phase 4: Attribute control charts replaced with variable charts, many charts deleted due to non-criticality or ineffectiveness
- Phase 5: Most charts are X-bar and R charts on key process parameters, some advanced charts (CUSUM, EWMA, etc)

# What if you react to common cause?



### Adjusting process back to center will increase overall variation

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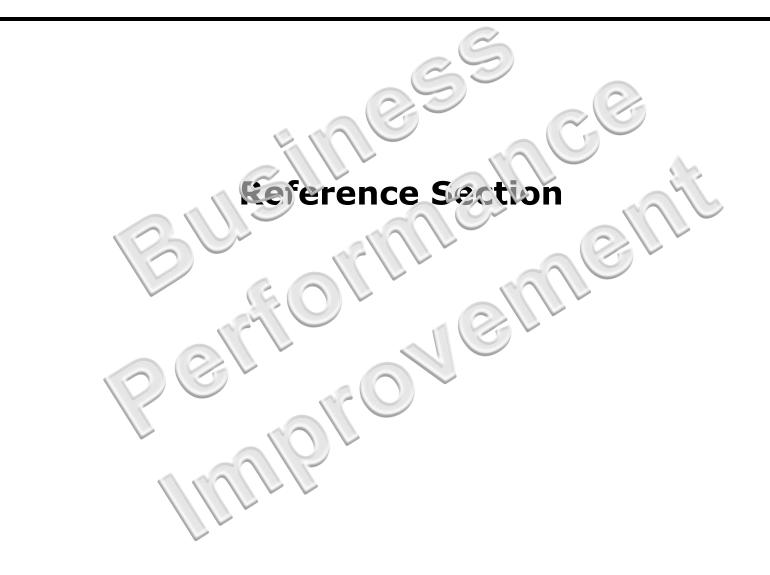


- Create a control chart and histogram before performing any data analysis or calculations
- Use at least 20 data points before calculating control limits
- Moving Range charts are optional, and not required with Individuals charts
- Spec limits may be displayed on individuals charts, but can lead to complacency, never on X-bar and K charts
- Apply SPC to the inputs of a process whenever possible
- Use X-bar and Standard Deviation (S) chart instead of Xbar and R chart when subgroup size > 5
- Special causes are indications of potential problems, they cannot guarantee that a problem exists
- Document any out of control condition observed on a chart, to show evidence that it was seen, and some investigation took place



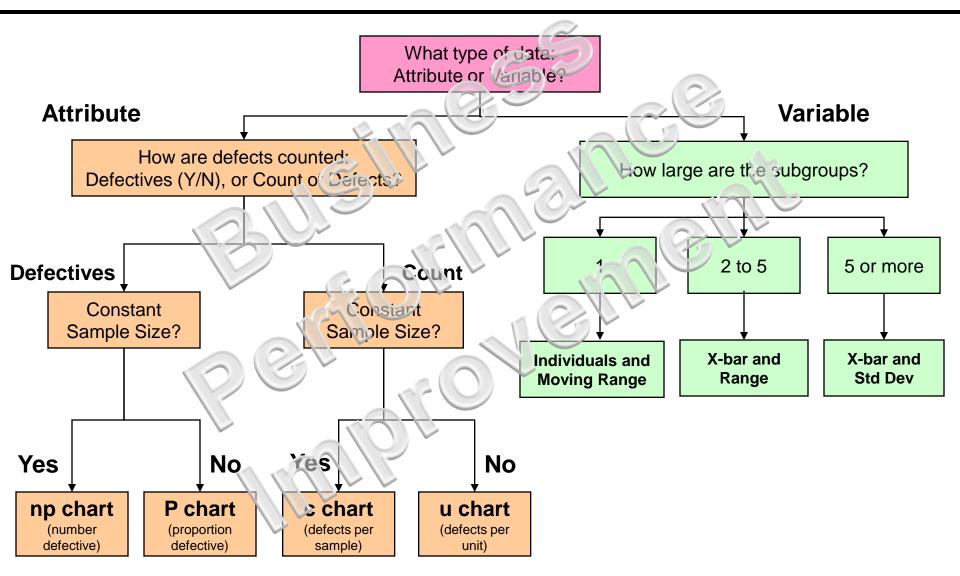
- Lack of commitment from management
  - Resistance to change from reactive to preventative
- Lack of training and education in SPC
  - Misinterpretation of control charts
  - Lack of focus and/or maintenance on control charts
- Inadequate measurement system in place (poor Gage R&R)







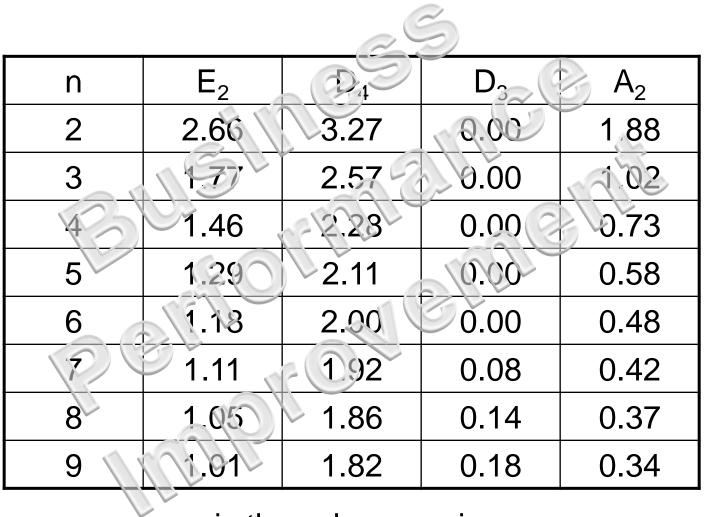
# **Decision Tree for Control Charts**



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# **Shewhart Control Chart Constants**



n is the subgroup size

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# **Additional Resources**

# Business Performance Improvement

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